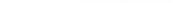


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/563,327	IMAI, AKIRA
	Examiner	Art Unit
	TAN Q. NGUYEN	3661

**SEARCHED**

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
701	300,207,1	1/19/2009	TN
340	436	1/19/2009	TN
455	456.1	1/19/2009	TN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS SEARCH	8/15/2008	TN
EAST SEARCH	8/14/2008	TN
Interference Search History Printout	1/19/2009	TN